

Verifying Analog Designs: Needs, Constraints and Future Challenges for Complex Analog Designs from Cells to System

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Outlook

- **Analog design context**
- **Cell design paradigm going below 65nm**
- **SoC design paradigm going below 65nm**
- **R&D Directions**

The background is a deep blue with a complex pattern of lighter blue, ethereal light rays or lens flares radiating from the center, creating a sense of depth and focus.

Analog design context

AMS IC's define today's killer products

- Most eye-catching features are supported by A/M-S IC's

- Transceivers

- GSM
- W-CDMA
- Bluetooth
- WLAN
- UMTS
- WiFi

- DC/DC converters

- Power management IC's

- A/V amplifiers

- Power amplifiers

- LCD drivers

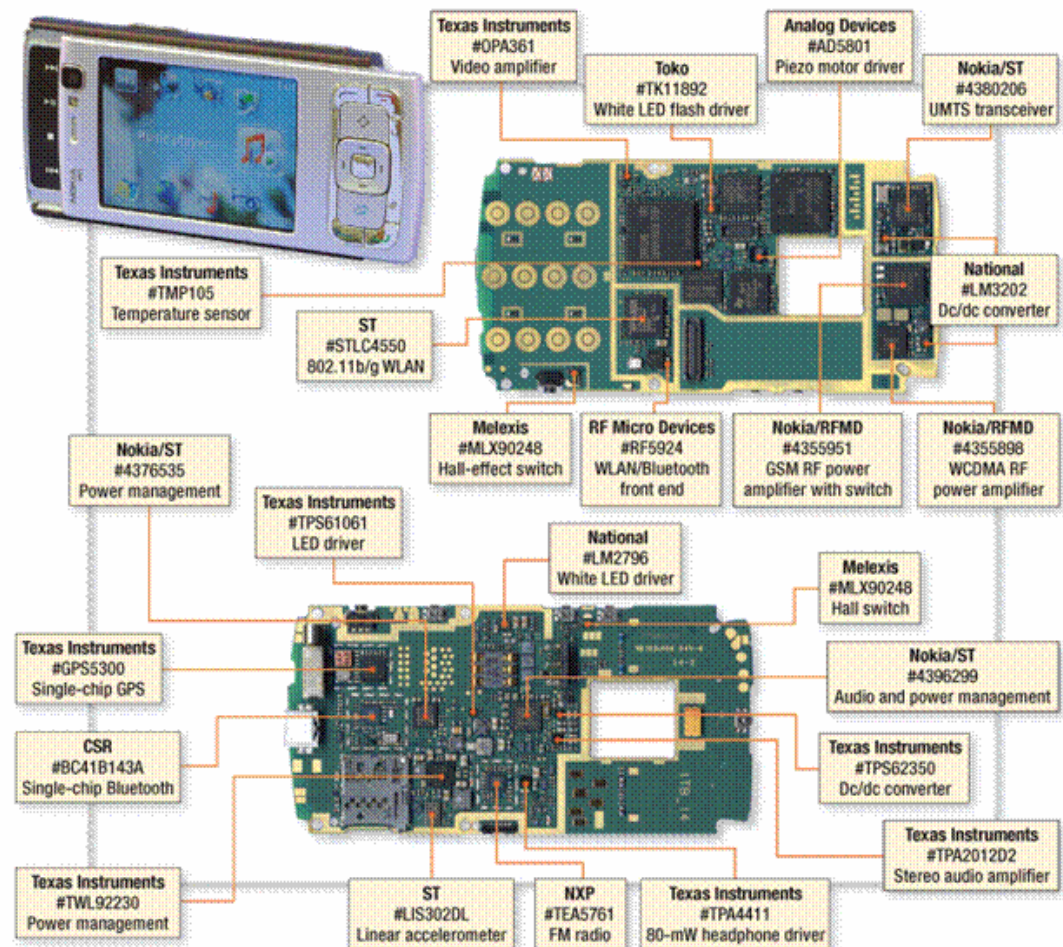
- Motor driver

- FM radio

- Sensors

- Flash memory

- etc



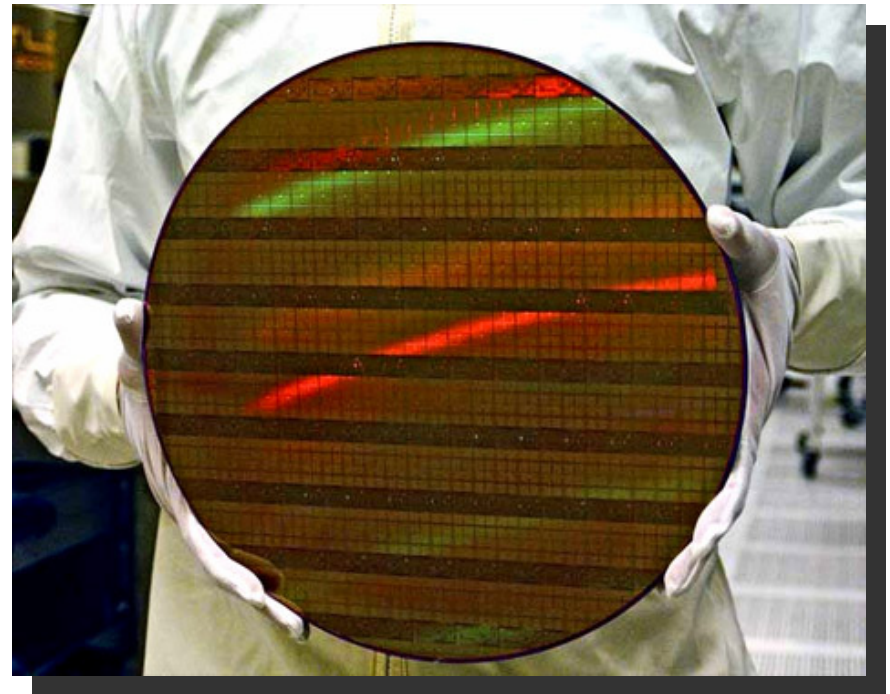
Problems with AMS SoC Verification

- Those who develop AMS SoC have 3 concerns which prevent them from sleeping well :

Will it be functionally correct ?

Will it be robust ?

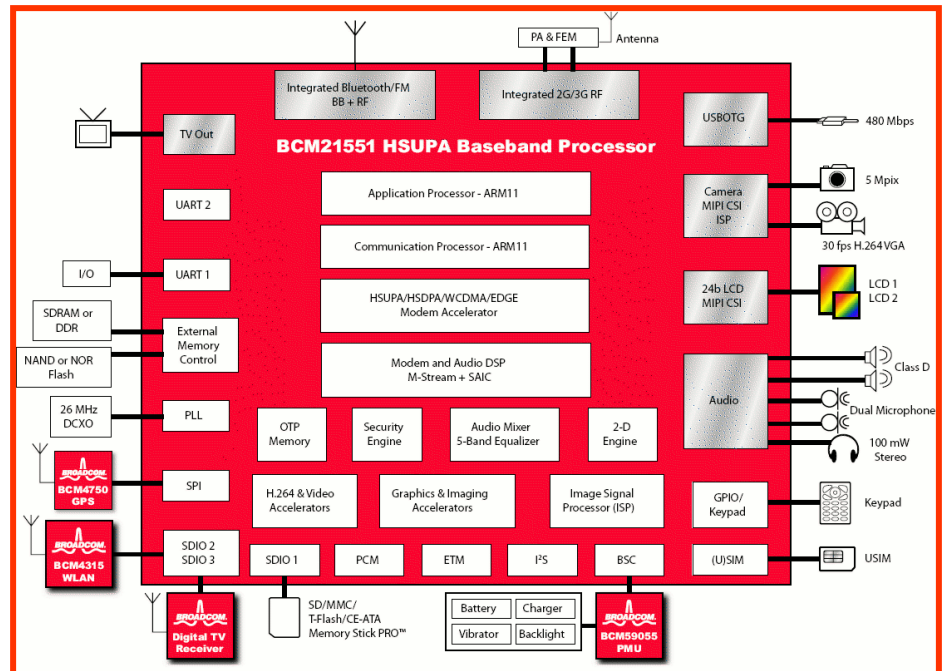
Will it be reliable ?



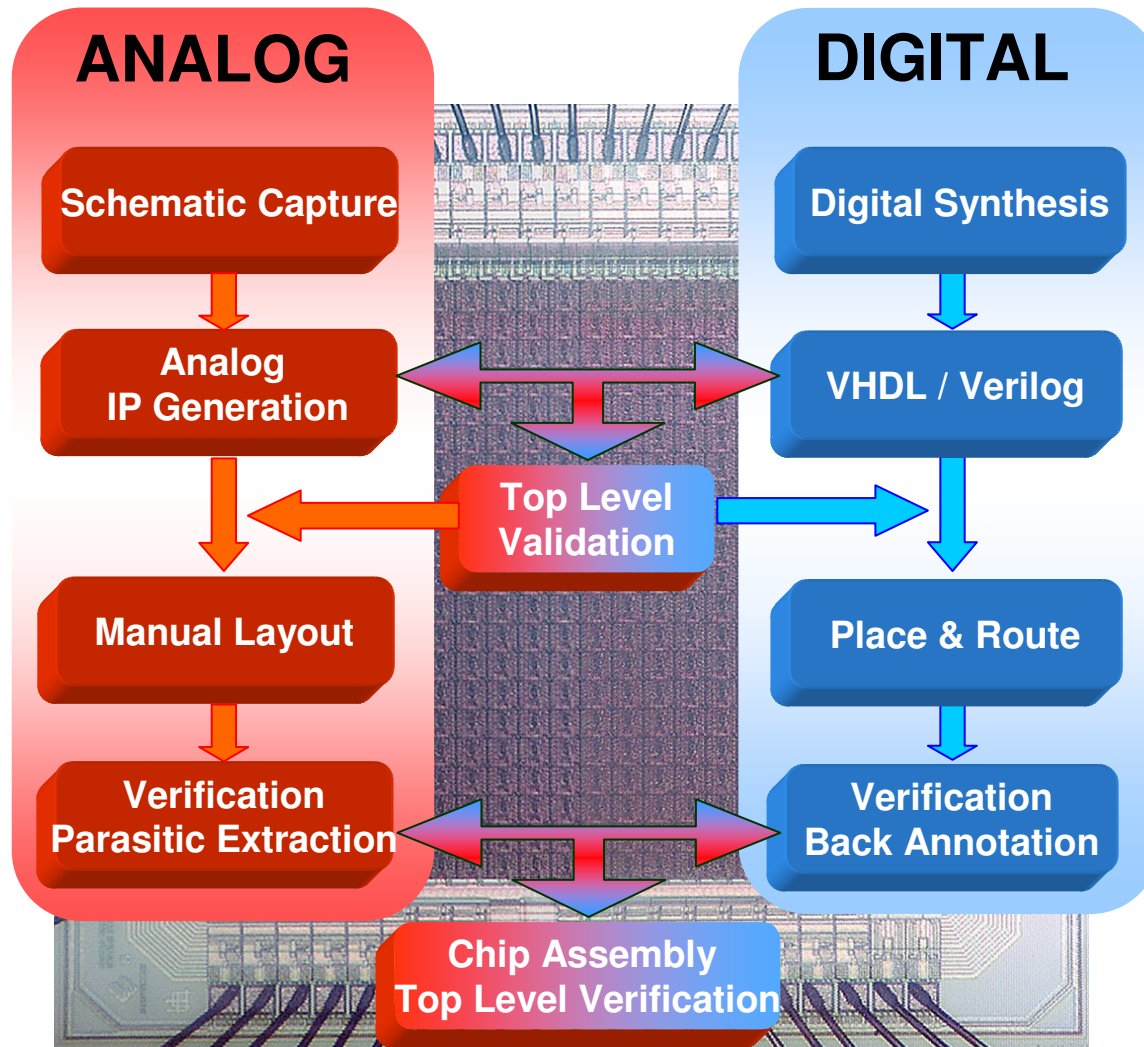
Will it be functional ?

- The end customer is waiting for a working prototype
- Challenge : assemble and verify, in less than one month :

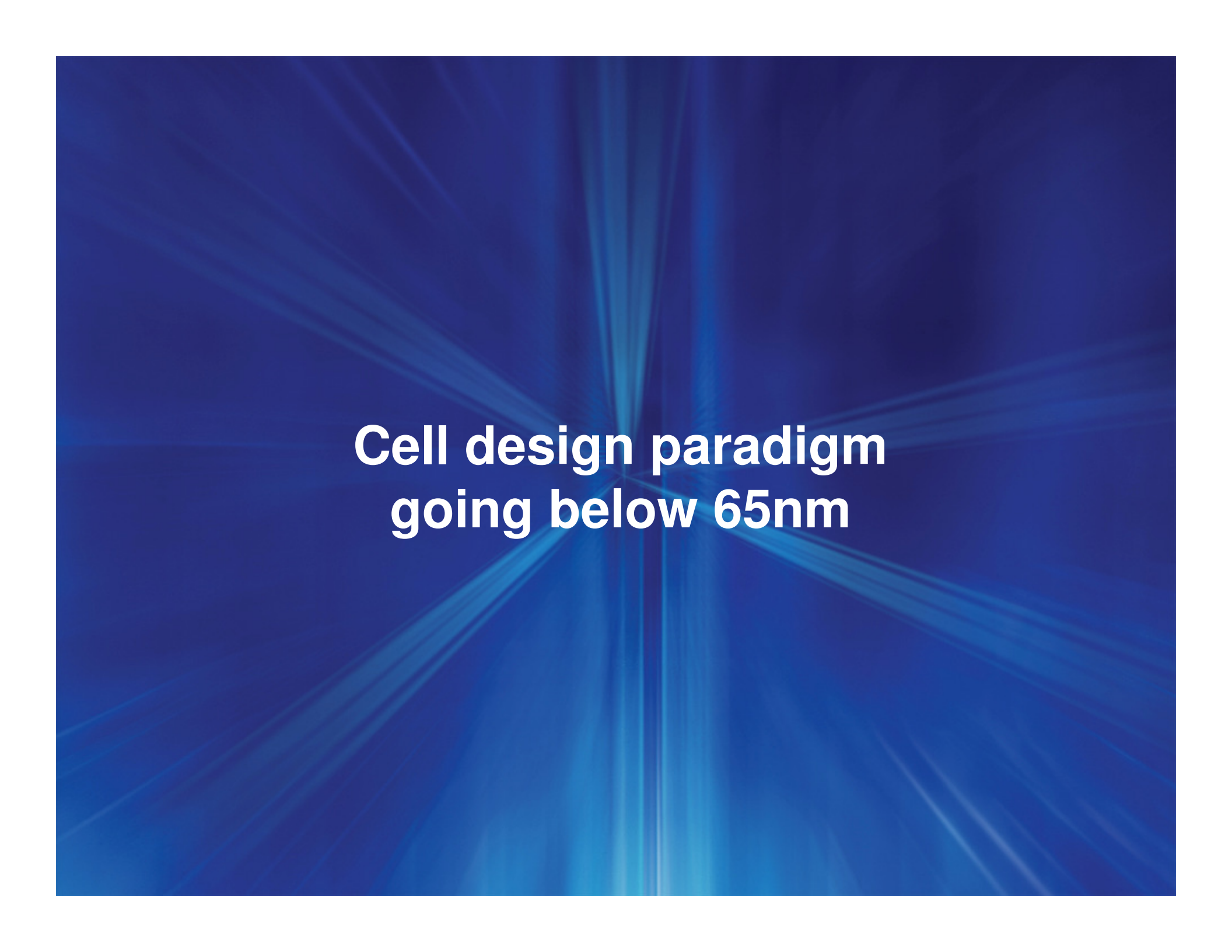
- Analog/RF cells
- 3rd-party HDL IP blocks
- Embedded RAM
- Custom logic
- SV testbench



AMS vs. Digital Design Flows



- Analog designers are facing several bottlenecks
 - No automation available in
 - Synthesis
 - P&R
 - Formal verification
- Increased complexity:
 - Smaller geometries of sub-micron processes allows bigger designs with more functionalities
- Increased process variability:
 - Dramatically critical in sub-micron processes
- TTM is under pressure
- Consequence: Analog designer must increase productivity in
 - Cell design
 - System validation

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**Cell design paradigm
going below 65nm**

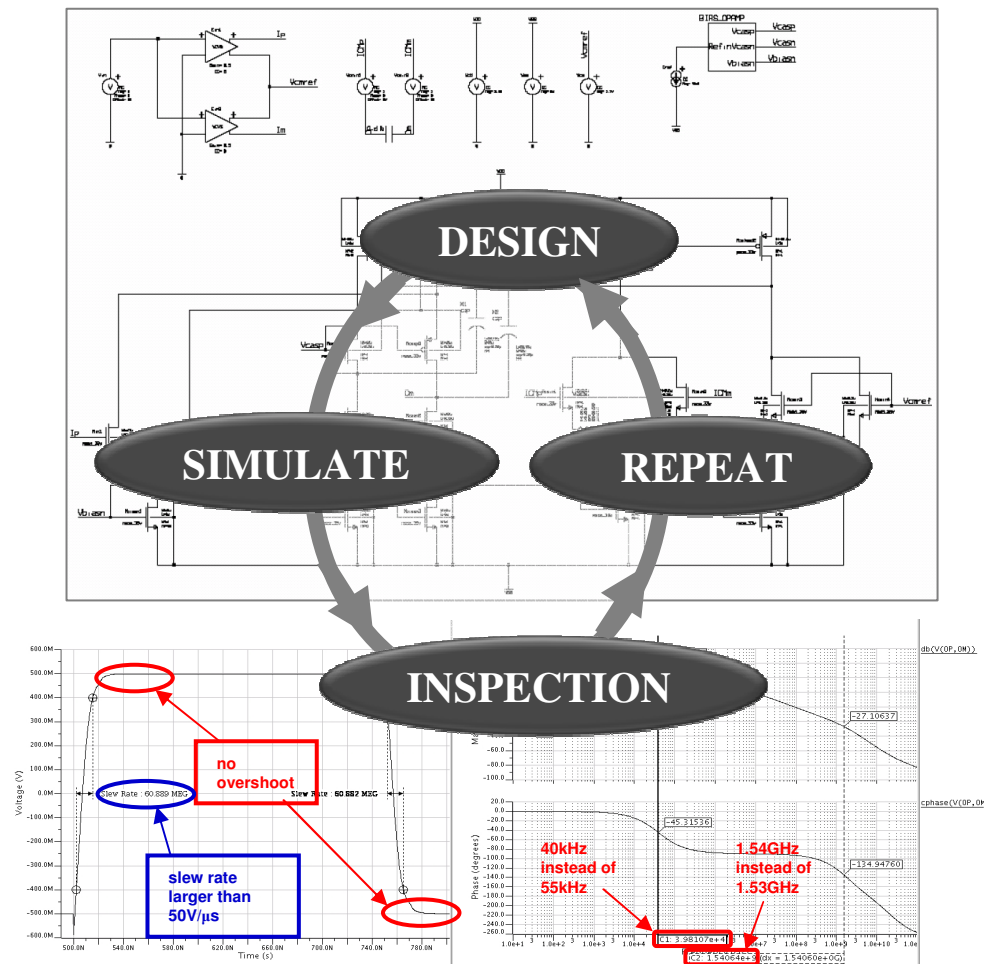
Analog Cell Functional Verification

■ Nominal

- SPICE simulations
- Waveform inspection
- Scripting

■ Worst case

- Voltage and temperature variations
- Process Corners



More Complex Simulations

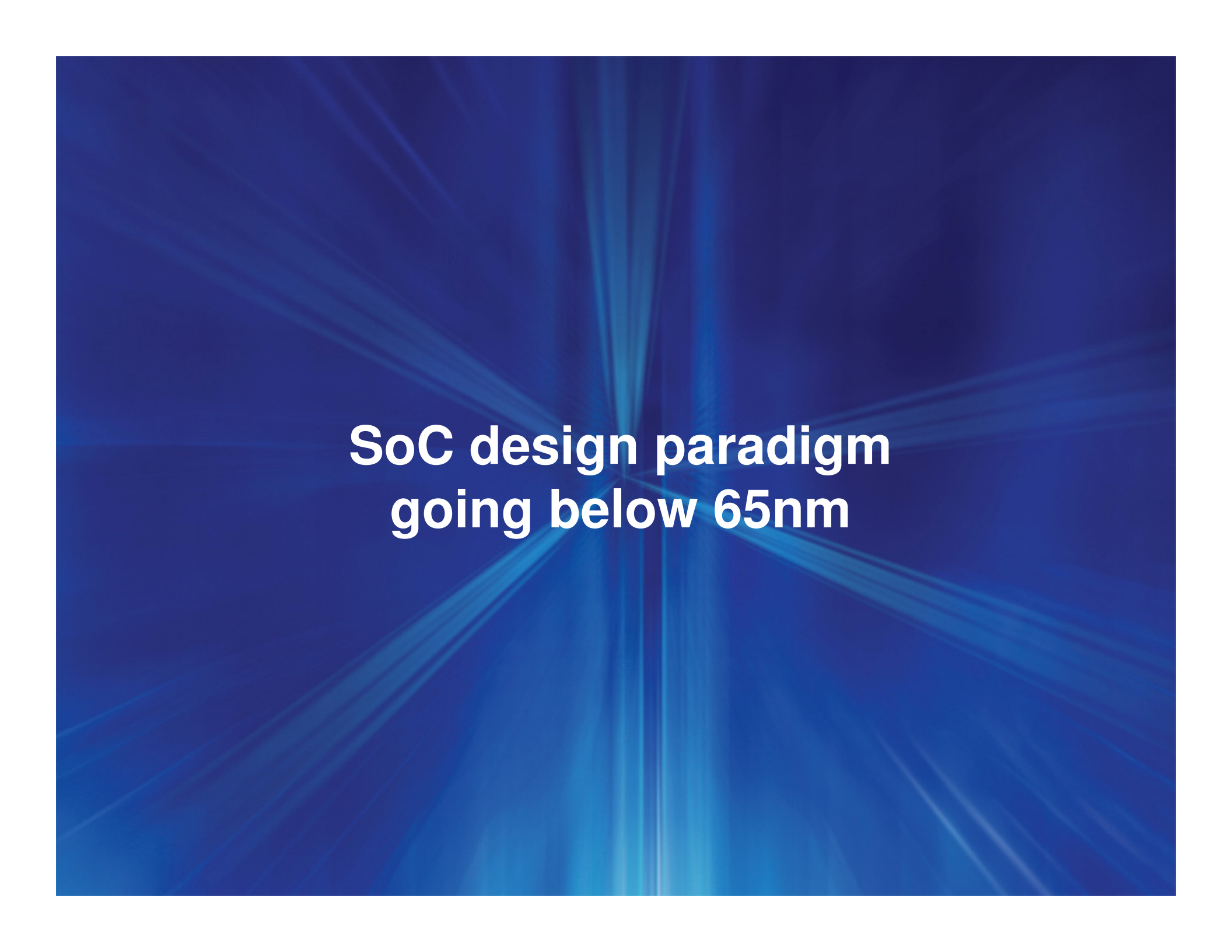
- Systems becoming more complex require complex AMS cells with more functionalities
- Nanometer processes have more effects (stress, dispersion ...) that make design phase more complex.
- Analog IP validation requires post layout simulation for accuracy
 - Reduction algorithms becoming critical
- Analog IP validation cannot be done anymore with corner-based simulations
- Simulations getting more complex with Digital/Analog/RF interactions

Increasing Number of Simulations

- Because of all possible configurations, a huge number of simulations has to be managed
 - For example, LDO regulator characterization: 41,000 simulations during 1 week.
- Possibility to improve design productivity with a simulation manager
 - Netlist creation
 - Simulation launch and distribution over the network
 - Results post processing with Pass/Fail flags
 - Results synthesis in documentation
- MGC proposing a simulation manager tool (ICanalyst)
 - Same LDO example takes now 1/2 day

Monte Carlo Simulation

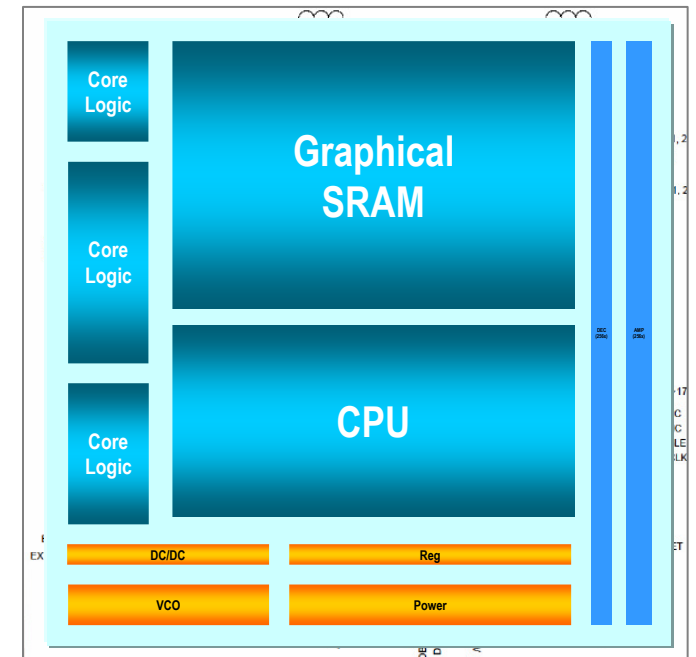
- **Monte-Carlo simulations are needed but simulation time explodes**
 - 100's of runs gives a rough guess on results
 - 20,000's runs needed for guaranteed tight accuracy
- **Solution 1: Enhance MonteCarlo (proposed by MGC in ICanalyst & soon in Eldo)**
 - QMC suites accelerate convergence (break $N^{-1/2}$ rate)
 - Adaptive MC stops when prescribed accuracy is obtained
 - Incremental MC allows continuation of MC simulation (add more runs)
- **Solution 2: Modeling can be used for simple problems without discontinuity**
 - Simulate sampled points to create a performance model
 - Run MC on the model
 - Can decrease the simulation time and get very accurate results with 20 000 (fast) MC runs from a model based on 100/150 simulations

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**SoC design paradigm
going below 65nm**

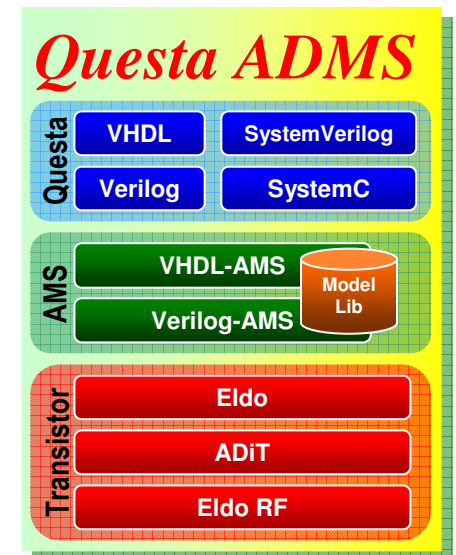
Approaches to AMS Verification

- **Tightly linked analog + digital functions make system-level simulation mandatory**
- **Most frequent Mixed-Signal SoC errors are integration errors**
 - Interconnect
 - Transposed buses
 - Control signals inverted
 - Un-tested operating modes
 - Multiple power domains

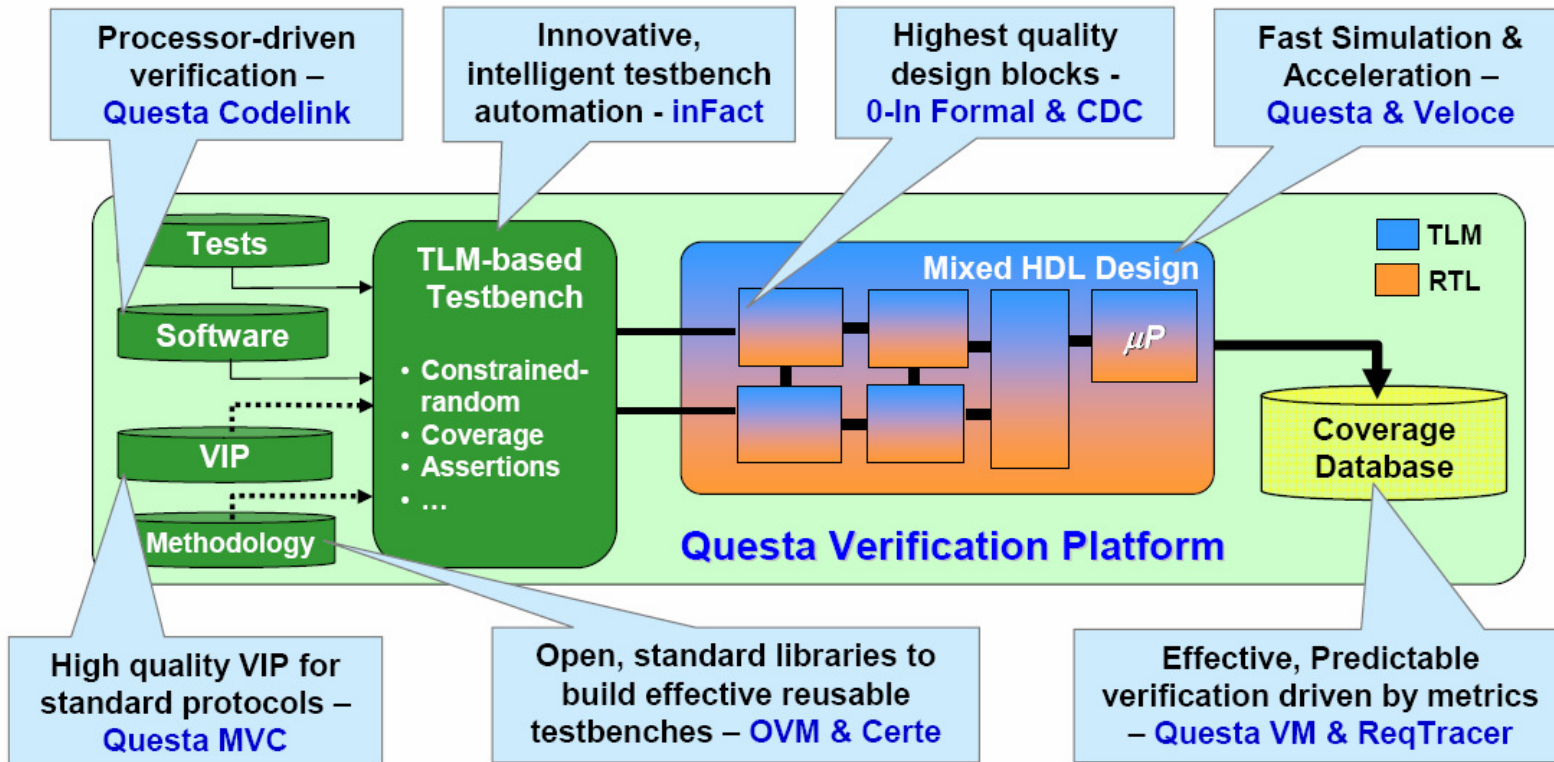


Problems to solve

- AMS SoC represents today multi-million transistors IC's with possibly few million analog
- Analog blocks representation is an issue:
 - Transistor → capacity problem, even with Fast-SPICE, makes simulation too slow
 - VHDL-AMS → investment in modeling needed, and still a little slow
 - VHDL-RN → equivalent in modeling investment, cannot capture all analog effects, simulate faster (pure digital simulation)
 - Solution: Checkerboard methodology to use the best accuracy compromise depending on which part of the design is activated by the test vector
 - Critical cells: SPICE or Fast-SPICE
 - Interacting cells: VHDL-AMS
 - Inactive cells : VHDL-RN or “level 0” VHDL-AMS
 - This is the solution developped by MGC (Questa ADMS)



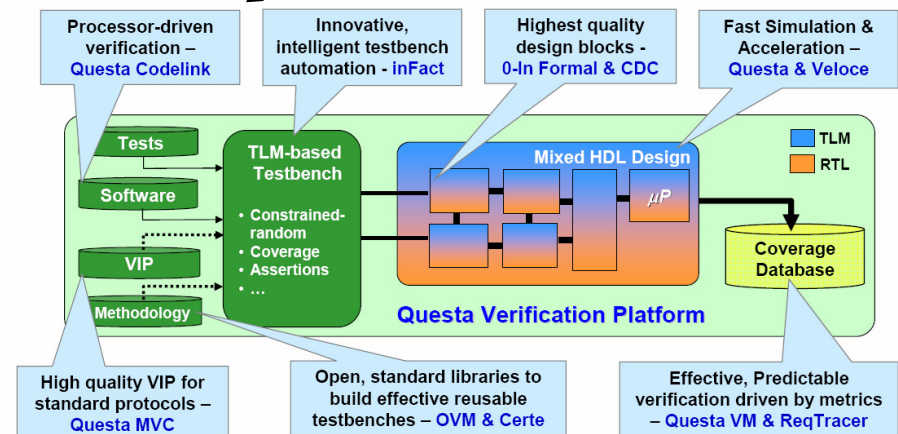
Digital SoC validations



- Not just a digital simulator
- Complete set of methodologies is needed

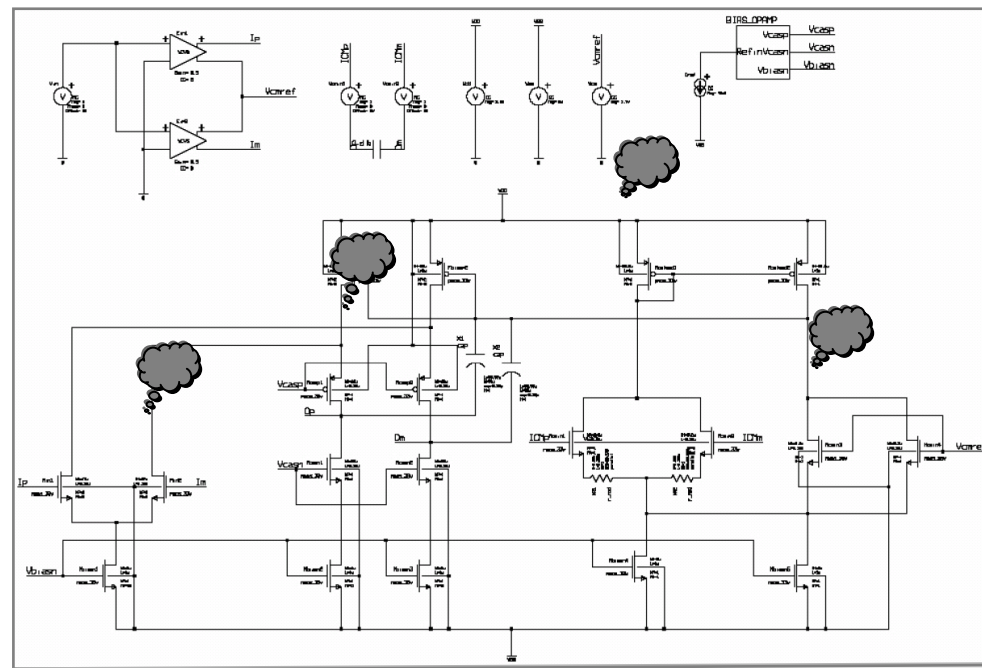
Needs for AMS SoC validations

- Need to transpose some digital techniques to AMS design
 - Test Bench Automation
 - Access advanced SPICE components in the digital testbench as behavioral models:
 - PWL source
 - Loads
 - Measurement checkers
 - OVM/SVA: need for a SVA Analog
 - Participation in Accelera standardization committee
 - Absolute time definition
 - Result comparison including tolerance

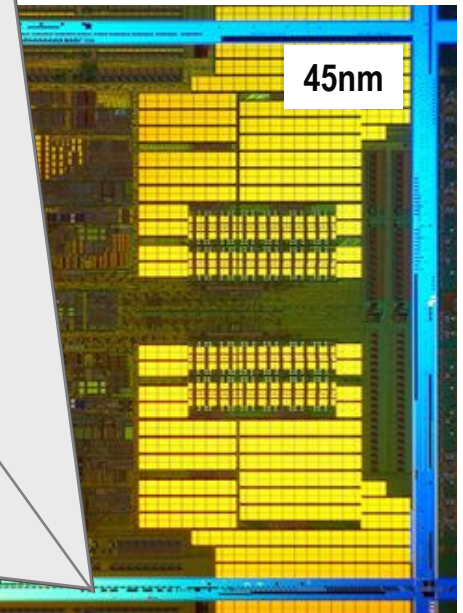


Assertions and Safe Operating Area

- ABV (Assertion Based Verifications) detects bugs at the source, saving valuable debug time
- Analog designers use SOA to detect malfunctions
- Dynamic assertion technology for mixed-signal



Safe Operating Area Check



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R&D Directions

Conclusion

- Analog IP design needs productivity improvement in both cell design and SoC validation
- Process below 65nm remove capacity/functionality bottleneck but opens design complexity/validation issues
- R&D directions
 - Statistical simulation
 - Full SoC formal validation (ABV, SVA-A)
 - Simulation time speed-up
 - More efficient algorithms
 - Multi-threading